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				Application Number	10/689,024
				Confirmation Number	4493
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				First Named Inventor	Takashi UDAGAWA
				Art Unit	2826
				Examiner Name	Minh Loan Tran
Sheet 1 of 1				Attorney Docket Number	Q72568

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ³ (if known)		
MLT		US 6,069,021		05-30-2000	TERASHIMA et al.
		US			
		US			
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		US			
		US			

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
MLT		JP	10-56202		02-24-1998	SHOWA DENKO KK	Abstract
MLT		JP	55-3834		01-26-1980		Abstract
MLT		JP	10-107315		04-24-1998	SHOWA DENKO KK	Abstract

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
MLT		Isamu AKASAKI (compiler), "Advanced Electronics Series, I-21, Group-III Nitride Semiconductor", 1 st edition, pp. 288-289, Baifukan (December 8, 1999)	Abstract
MLT		Isamu AKASAKI et al.; "Effects of AlN Buffer Layer on Crystallographic Structure and on Electrical and Optical Properties of GaN and Ga _{1-x} Al _x N (0 < x ≤ 0.4) Films Grown on Sapphire Substrate by MOVPE"; Journal of Crystal Growth (the Netherlands); Vol. 98, pp. 209-219 (1989)	
MLT		Isamu AKASAKI (compiler); "Advanced Electronics Series, I-21, Group-III Nitride Semiconductor"; 1 st edition, pp. 211-213, Baifukan (December 8, 1999)	Abstract

Examiner Signature	Minh Loan Tran	Date Considered	8/05
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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